

U.S. DEPARTMENT OF ENERGY

FIELD WORK PROPOSAL

1. WORK PROPOSAL NO.: JLAB-HEP-XX	2. REVISION NO.: 1	3. DATE PREPARED: 2/06
4. WORK PROPOSAL TITLE: Understanding, Control, and Elimination of "Dark Current" Sources		5. BUDGET AND REPORTING CODE:
6. WORK PROPOSAL TERM: 10/1/2006 to 3/30/07		
7. HEADQUARTERS OFFICE PROGRAM MANAGER: Robin Staffin, Assoc. Dir., HEP (301) 903-3624 hep-tech@science.doe.gov	8. HEADQUARTERS ORGANIZATION: Office of High Energy Physics, SC-20	
9. DOE FIELD ELEMENT WORK PROPOSAL REVIEWER: Jim Turi, (757) 269-7146, turi@jlab.org	10. DOE FIELD ELEMENT: Oak Ridge Operations	
11. CONTRACT WORK PROPOSAL MANAGER: Swapan Chattopadhyay, (757) 269-7001 swapan@jlab.org	12. CONTRACTOR NAME: Southeastern Universities Research Association, Inc., Thomas Jefferson National Accelerator Facility (Jefferson Lab)	

13. Work Proposal Description

Principal Investigators: Charles Reece

Develop a quantitative characterization of contaminants that present "dark current" risks to SRF accelerator cavities. Using existing infrastructure and analysis tools at JLab, perform a systematic assessment of actual sources present and created in the production environment, identify specific mitigation techniques, develop relevant standardized model contaminants, and initiate use of such models for systematic characterization of the effectiveness of various proposed cleaning techniques and the development of optimization strategies for the use of such techniques. The benefit will be increased reliability of production of "dark-current-free" high performance SRF cryomodules and reduced cost by providing an improved basis for process design engineering. Attainment of such is to a successful realization of an ILC.

14. CONTRACTOR WORK PROPOSAL MANAGER	15. OPERATIONS OFFICE REVIEW OFFICIAL
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16. DETAIL ATTACHMENTS

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|---|---|--|
| <input type="checkbox"/> a. Facility Requirements
<input type="checkbox"/> b. Publications
<input checked="" type="checkbox"/> c. Purpose
<input checked="" type="checkbox"/> d. Background
<input checked="" type="checkbox"/> e. Approach | <input type="checkbox"/> f. Technical Progress
<input type="checkbox"/> g. Future Accomplishments
<input checked="" type="checkbox"/> h. Relationships to Other Projects
<input type="checkbox"/> i. NEPA Projects
<input type="checkbox"/> j. Milestones | <input type="checkbox"/> k. Deliverables
<input type="checkbox"/> l. Performance measures/expectations
<input type="checkbox"/> m. ES&H Considerations
<input type="checkbox"/> n. Human/Animal Subjects
<input type="checkbox"/> o. Other (Specify) |
|---|---|--|

**WORK PACKAGE REQUIREMENTS FOR OPERATING/EQUIPMENT
OBLIGATIONS AND COSTS**

CONTRACTOR NAME: Southeastern Universities Research Association, Inc. Thomas Jefferson National Accelerator Facility (Jefferson Lab)		WORK PROPOSAL #: JLAB-HEP-XX	REV. #: 1	DATE PREPARED: 2/06	
17. STAFFING (IN STAFF YEARS) a. SCIENTIFIC b. OTHER DIRECT c. TOTAL DIRECT	<u>FY 2006 Allocated</u>	<u>FY 2007 Target</u>	<u>FY2008 Target</u>	<u>FY 2007</u> Requirements Authorized	
		1.0	0.5		
		2.0	1.0		
		3.0	1.5		
18. OPERATING EXPENSE (in thousands) a. TOTAL OBLIGATIONS (B/A) b. TOTAL COSTS (B/O)		550	220		
		550	220		
19. EQUIPMENT (in thousands) a. EQUIP OBLIGATIONS (B/A) b. EQUIPMENT COSTS (B/O)					
20. MILESTONE SCHEDULE (Tasks) Establish standarized contamination assessment protocol Assess contaminant distributions from hardware assembly Evaluate new "standard contaminants" Contaminant distributions measured from vacuum system Identify improved assembly techniques Compare cleaning effectiveness between BCP and EP surfaces and optimize – ultrasonic Compare cleaning effectiveness between BCP and EP surfaces and optimize – HPR		<u>Dates</u>	<u>Proposed \$</u>	<u>Authorized \$</u>	
		02/2007	\$200k		
		06/2007	\$70k		
		08/2007	\$50k		
		09/2007	\$70k		
		09/2007	\$105k		
		10/2007	\$110k		
		03/2008	\$165k		
21. REPORTING REQUIREMENTS (Description): Quarterly budget reports, biannual technical progress reports.					

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16. c. Purpose
Contamination QA

Contaminants that can cause dark current and degrade cavity performance come from "non-clean" components and from "clean" components that shed by abrasion. Hardware and techniques used for handling, sealing, and evacuating "clean" cavities must be thoroughly characterized with respect to their potential for contributing performance-limiting contaminants during processing, handling, storage, assembly, evacuation, or maintenance.

This activity proposes to yield

1. Characterization of actual contaminants that present field emission (dark current) risks to SRF cavities when present techniques are employed.
2. Screening criteria by which materials and handling techniques will be selected to minimize generation of contaminating particulates from formerly "clean" materials – keeping cavities clean.
3. Identification of suitable contamination "standards" to aid characterization and design of maximally effective cleaning techniques.
4. Initial use of the standard contaminants to assess the relative effectiveness of potential surface cleaning protocols.

16. d. Background

The phenomenon of "dark current" is a major concern for the superconducting cavities in the ILC. Dark current is an electron current that flows in the superconducting linac from sources within the cavities themselves, rather than being injected from an external source, as is the main beam. Dark current arises from particulates randomly distributed over the interior surfaces of the cavities that emit electrons when subjected to high electric fields. Dark current does not contribute to luminosity, but does reduce the efficiency of acceleration, increases heat loads at 2K and is the primary source of background radiation in the accelerator itself, causing radiation damage to components. Understanding and control, leading to elimination of the sources of dark current is the subject of this proposal.

JLab is in a unique position to promptly undertake this task due to the availability of powerful analytic tools in close proximity to on-going cryomodule assembly activities already working with 2nd-generation disciplined production techniques.

JLab has a scanning field emission microscope (SFEM) integrated with an SEM with EDS analysisⁱ, a field emission viewer (FEViewer) system, and a fully equipped surface science lab for pursuing any correlation of surface morphology with susceptibility to contaminant adhesion.ⁱⁱ

16. e. Approach

A.

Develop standard qualification tests relevant to SRF application for observing particulates generated from the materials present in the cleanroom and beamline vacuum space. This extends the work reported by Bonin and Reschke,ⁱⁱⁱ using new tools to establish a qualification protocol.

- Disciplined use of airborne and in-line particle counters to sense migration of particulates within the assembly cleanroom.
- "Watch-plate" tests with analysis in FEViewer, Scanning Field Emission Microscope (SFEM), SEM/EDS, and laser surface scanners.

ⁱ T. Wang, C. E. Reece, and R. M. Sundelin, "Direct Current Scanning Field Emission Microscope Integrated with Existing Scanning Electron Microscope" Rev. Sci. Instrum. **73** 3215 (2002).

ⁱⁱ <http://srf.jlab.org/SurfaceScienceLab.htm>

ⁱⁱⁱ Bonin et al. "Field Emission Studies at Saclay", 6th SRF Workshop, CEBAF, 1993, p. 1033; and D. Reschke, "New Aspects of Quality Control during Preparation of TTF 1.3 GHz cavities", 9th SRF Workshop, Los Alamos, p. 159.

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B:

Using standardized methods, characterize the particulates generated by well-defined "representative" actions with "typical" components associated with cavity preparation and assembly.^{iv} The objective is to determine the size and material distribution of particulates generated by these actions in order to better inform the efforts to avoid the contaminants and to remove them.

- Screw assembly and tightening
- Conflat flange assembly
- Flat-on-flat like-material rubbing
- Valve actuation
- External impact generation
- Bleed-up and pump-down of completed beamline assemblies
- Nearby human activity

C:

Establish objective and quantitative evaluation criteria for activities and techniques that present contamination risks to clean cavities. Identify principal vulnerabilities and develop improvement strategies. Propagate both the evaluation criteria and accumulating technique guidance to the community.

D:

Based on results from **B**, identify three or four candidates for reproducible "standard" contaminants (most likely, metal powders).

- Identify commercial sources of such materials.
- Develop standardized contamination methods using the powders.
- Evaluate such materials with respect to their similarity to "found" contaminants with respect to field emission properties.

E:

Develop and implement systematic evaluation of the effectiveness of various cleaning techniques applied to representative Nb (BCP, EP, etc.) and other surfaces after controlled exposure to the standardized contaminants.

- Enhanced sensitivity to the effectiveness of proposed cleaning techniques is obtained by the deliberate enhancement of the contaminant density.
- Ultrasonic - Megasonic
- Removal efficiency of HPR as a function of various nozzle, flow, and geometrical factors. This should dovetail with the HPR nozzle optimization studies of P. Michelato, INFN Milan.^v
- IPA cleaning.

16. h. Relationships to Other Projects

Contaminants are commonly accepted as presenting risks to the performance of high-gradient SRF cavities. Qualitative strategies have been deployed to control such contamination sources and to implement cleaning methods. The international community lacks a quantitative assessment standard with which to characterize the risks and the remedies. This work will seek to establish a common metric for identifying risk sources for dark current and to begin providing guidance to the ILC community on specific risk reduction strategies.

^{iv} This extends the work of A.Matheisen, D. Reschke; "Control of Particle Contamination with Liquid and Air particle Counters during Preparation of the TTF 1.3 GHz Resonators", LNL-INFN 133/98, p. 640 to better understand the size distribution of contaminants produced.

^v See presentation TTCM, LNF Dec. 2005